Qualification Test Report

1. Introduction

1.1 Objective

Testing was performed on the USB Type-C Receptacle and Plug Lead Free Version connectors to determine if it meets the requirements of Product Design Objective 108-115129-2.

1.2 Scope

This report covers the electrical, mechanical and environmental performance requirements of the USB Type-C Receptacle and Plug Lead Free Version connectors.

1.3 Conclusion

The USB Type-C Receptacle and Plug Lead Free Version connectors, meets the electrical, mechanical and environmental performance requirements of Product Specification

1.4 Product Description

The USB Type-C Lead Free Version connectors are cable mounted plugs and printed circuit mounted receptacles. The contacts are made of a copper alloy with gold over nickel plating in contact area, gold flash plating on solder area all over nickel plating. The housing material is thermoplastic UL94V-0 rated.

1.5 Test Samples

The test samples were representative of normal production lots, and samples identified with the following part numbers were used for test:

| Test Group | Quantity | Part Number | Description |
|---|-----------------------|-------------|--|
| A-1,A-2,A-3,A-4,A-7, B-1,B-6, C-1,C-2 | Refer to test result. | 2305018-2 | Receptacle Assembly (IPX8) |
| A-1,A-2,A-3,A-4,A-7, B-1,B-6, C-1 | Refer to test result. | 1-2305018-2 | Receptacle Assembly (NONE WATER PROOF) |

1.6 Environmental Conditions

Unless otherwise stated, the following environmental conditions prevailed during test:

Temperature: 15°C to 35°C Relative Humidity: 25 to 85%

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2. Test Method

Test requirement and Procedures summary

| Test Item | Procedures | Requirements |
|---------------------------------------|---|--|
| Visual Inspection | EIA 364-18B | Visual inspection samples |
| | | shall be free from defect such as damage, deformation, blister and burrs that are detrimental to the function and appearance. |
| Electrical | | <u> </u> |
| Low Level Contact Resistance | EIA 364-23 The low level contact resistance (LLCR) measurement is made across the plug and receptacle mated contacts and does not include any internal paddle cards or substrates of the plug or receptacle. See Figure 1 Measure at 20mV (max) open circuit at 100 mA | 40 m Ω (Max) initial for VBUS, GND and all other contacts. 50 m Ω Maximum after initial measurement. |
| Continuity | See USB Type C Compliance Document Appendix E. | No discontinuities or shorts allowed. |
| Dielectric Withstanding Voltage | EIA-364-20, Method B. Applicable to both receptacle and plug. 100VAC (rms) for 1 minute at sea level. | No break down shall occur when voltage is applied between adjacent contacts of unmated and mated connectors |
| Insulation Resistance | EIA 364-21 Applicable to both receptacle and plug. Apply 500V DC Apply the above specified voltage between adjacent contacts for 1 minute. | >100 $\mbox{M}\Omega$ insulation resistance between adjacent contacts of unmated and mated connectors |
| Current Rating | EIA 364-70, Method 2. See USB Type C Compliancy Document Appendix C. A current of 5.0 A shall be applied collectively to VBUS pins (i.e., pins A4, A9, B4, and B9) and 1.0 A applied to the SBU1/SBU2 pin (i.e., A8/B8 of the plug connector) with the return path through the corresponding GND pins (i.e., pins A1, A12, B1, and B12). A minimum current of 0.25 A shall also be applied individually to all the other contacts. Allow to stabilize. Note: special T-rise test boards design per the guidelines in Appendix C of the USB Type C Compliancy Document are to be used. | Temperature rise of the outside shell surface of the mated connector pair above the VBUS and GND contacts shall not exceed 30°C above ambient temperature. |

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| Test Item | Procedures | Requirements |
|------------------------------------|--|---|
| Mechanical | | |
| Insertion Force | EIA-364-13 Maximum rate 12.5mm/min | Between 5N and 20N |
| Extraction Force | EIA-364-13 Maximum rate 12.5mm/min | Initial: 8 N to 20 N; After test: 6 N to 20 N |
| Durability | EIA 364-09 10,000 cycles | No evidence of physical damage |
| Durability (Preconditioning) | EIA 364-09 50 cycles | No evidence of physical damage |
| Reseating | Manually unplug/plug the connector. Perform 3 such cycles | No evidence of physical damage |
| 4-Axis Continuity Test | See USB Type C Compliancy Document Appendix D for detailed test fixtures and procedures. Plug and Receptacle: Subject the mating interface to the moments defined in USB Type C Compliancy Document Appendix D for at least 10 seconds. | No discontinuities greater than 1 microsecond duration in any of the four orientations tested. |
| Environmental | Appendix 5 for defease 10 seconds. | |
| Temperature Life Temperature Life | EIA-364-17,Method A 105°C without applied voltage for 120hrs EIA-364-17, Method A | Low level contact resistance meets spec before and after the Temperature Life test. Low level contact resistance meets spec before |
| (Preconditioning) | 105°C, 72hrs | and after the Temperature Life test. |
| Thermal Shock | EIA-364-32, Method A, Condition I, duration A-4 (-55°-+85°C, 10 cycles) | No evidence of any physical damage. Low level contact resistance meets spec before and after the Thermal Shock test. |
| Cyclic Temperature and Humidity | EIA-364-31, Method III, w/o optional cold shock and vibration. Exceptions per EIA-364-1000: - Cycle between 25°C/80%RH and 65°C/50%RH. - Ramp 0.5hr, dwell 1hr, dwell starts when conditions are stabilized. - 24 cycles total - Allowable variation ±3°C and ±3%RH | No evidence of any physical damage. Low level contact resistance meets spec before and after the Thermal Shock test. |
| Vibration | EIA-364-28, Condition VII-D, 15min in each of 3 mutually perpendicular directions. Both mating halves should be fixed rigidly. (Power Spectral Density 0.02g2/Hz, Overall rms 3.10g) | No evidence of physical damages and no discontinuity longer than 1 microsecond. |
| Mixed Flowing Gas | EIA-364-65, class IIA, 112hrs unmated, 56hrs mated (168hrs total). | No evidence of any physical damage. Low level contact resistance meets spec before and after the Thermal Shock test. |
| Thermal Disturbance | Cycle the mated connector pair 10 times between 15°C and 85°C ramp > 2°C/min - dwell > 5 mins (ensure contacts reach temperature) - Humidity not controlled | Low level contact resistance meets spec before and after the test. |

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| Test Item | Procedures | | Requirements | | |
|--|-----------------------------------|-----------------|------------------|------------|------|
| Other | | | | | |
| | | | | | |
| Solderability | molten solder at a temperature of | | solder coverage. | n of 95% | |
| Water Ingression (selective for different P/N) | IEC 60529 – IPX8 | | | | ar e |
| | ctive for | | | | |
| | | | | | |
| | | | | | |
| | | | | | |
| molten solder at a temperature of +255°C ± 5°C at rate of 25.4 mm ± 6.35 mm per second. Hold in solder for 5 +0/-0.5 seconds. To include solder pins and mounting pads. Water Ingression (selective for IEC 60529 – IPX8 1.5m/30 minutes, No water is allowed the enclosure. Use water contact detective for | | | | | |
| | | | | | |
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| Test | A-1 | A-2 | A-3 | A-4 | A-7 | B-1 | B-6 | C-1 | C-2 |
|------------------------------------|-------|---------|-------|------------|-------|-----|-----|-----|-----|
| | '`- | , , _ | 7.0 | | , , , | | | | |
| Visual Inspection | 1,8 | 1,10 | 1,8 | 1,12 | 1,13 | 1,3 | 1,3 | 1,3 | 1,3 |
| Low Level Contact Resistance | 2,5,7 | 2,5,7,9 | 2,5,7 | 2,5,7,9,11 | 3,10 | | | | |
| Dielectric Withstanding Voltage | | | | | 2,11 | | | | |
| Insulation Resistance | | | | | 12 | | | | |
| Durability | | | | | 7 | | | | |
| Durability (Preconditioning) | 3 | 3 | 3 | 3 | | | | | |
| Insertion Force | | | | | 5,8 | | | | |
| Extraction Force | | | | | 6,9 | | | | |
| Temperature Life | 4 | | | 4 | | | | | |
| Temperature Life (Preconditioning) | | | 4 | | | | | | |
| Reseating | 6 | 8 | | 10 | 4 | | | | |
| Thermal Shock | | 4 | | | | | | | |
| Cyclic Temperature and Humidity | | 6 | | | | | | | |
| Vibration | | | 6 | | | | | | |
| Mixed Flowing Gas | | | | 6 | | | | | |
| Thermal Disturbance | | | | 8 | | | | | |
| Current Rating | | | | | | | 2 | | |
| 4-Axis Continuity Test | | | | | | 2 | | | |
| Solderability | | | | | | | | 2 | |
| Water Ingression | | | | | | | | | 2 |

C-1: Additional test, not part of USB Type C Compliance Requirements C-2: Additional test, selection item for water proof product.

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4 Test Result

| Group | Test Item | No. | Condition | | | Result | | Requirement | Judgment |
|-------|------------------------------------|-----|-----------|--------------------|--------------------|------------------------|---------------------|------------------------|----------|
| | Examination of Product | 5 | Initial | Max | Min No physic | Ave al damage | Unit | No | Pass |
| | LLCR | 5 | Initial | 26.47 | 21.84 | 24.08 | mΩ | Abnormalities 40Max | Pass |
| | Durability (Preconditioning) | 5 | Final | | | al damage | | No | Pass |
| | | | | | | | | Abnormalities No | |
| A-1 | Temperature Life | 5 | Final | | No pnysic | al damage | | Abnormalities | Pass |
| | LLCR | 5 | Final | 30.97 | 24.69 | 28.68 | mΩ | 50Max | Pass |
| | Reseating | 5 | Final | | No physic | al damage | | No Abnormalities | Pass |
| | LLCR | 5 | Final | 26.44 | 22.28 | 25.06 | mΩ | 50Max | Pass |
| | Examination of Product | 5 | Final | No physical damage | | No Abnormalities | Pass | | |
| | Examination of Product | 5 | Initial | | No physic | al damage | | No Abnormalities | Pass |
| | LLCR | 5 | Initial | 27.65 | 16.90 | 23.74 | mΩ | 40Max | Pass |
| | Durability (Preconditioning) | 5 | Final | | No physic | al damage | | No Abnormalities | Pass |
| | Thermal Shock | 5 | Final | | No physical damage | | No Abnormalities | Pass | |
| | LLCR | 5 | Final | 32.19 | 27.55 | 29.58 | mΩ | 50Max | Pass |
| A-2 | Cyclic Temperature and Humidity | 5 | Final | | No physic | al damage | | No Abnormalities | Pass |
| | LLCR | 5 | Final | 27.83 | 21.19 | 24.83 | mΩ | 50Max | Pass |
| | Reseating | 5 | Final | | No physic | al damage | | No Abnormalities | Pass |
| | LLCR | 5 | Final | 27.46 | 22.70 | 25.01 | mΩ | 50Max | Pass |
| | Examination of Product | 5 | Final | | No physic | al damage | | No Abnormalities | Pass |
| | Examination of Product | 5 | Initial | | No physic | al damage | | No Abnormalities | Pass |
| | Dielectric Withstanding Voltage | 5 | Initial | No br | eakdown or | flashover oc | curred | No Abnormalities | Pass |
| | LLCR | 5 | Initial | 31.92 | 26.52 | 29.65 | mΩ | 40Max | Pass |
| | Durability (Preconditioning) | 5 | Final | | No physic | al damage | | No Abnormalities | Pass |
| A-3 | Temperature Life (Preconditioning) | 5 | Final | | No physic | al damage | | No Abnormalities | Pass |
| | LLCR | 5 | Final | 27.54 | 22.43 | 25.63 | mΩ | 50Max | Pass |
| | Vibration | 5 | Final | Disconti | nuity less tha | an 1 µs all co ries | ontacts in | No Abnormalities | Pass |
| | LLCR | 5 | Final | 31.92 | 26.52 | 29.65 | mΩ | 50Max | Pass |
| | Examination of Product | 5 | Final | | No physic | al damage | | No Abnormalities | Pass |

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| Group | 1 | Test Item | No. | Condition | Mov | | st Result | Unit | Requirement | Judgr | ment |
|-------|---|------------------------------|---------|-----------|----------|---------------|-----------------------|---------------|------------------------|-------|------|
| | Examin | ation of Product | 5 | Initial | Max | Min No phy | Ave sical damag | Unit e | No Abnormalities | Pa | iss |
| | | LLCR | 5 | Initial | 27.54 | 22.43 | 25.63 | mΩ | 40Max | Pa | iss |
| | Durability | (Preconditioning) | 5 | Final | | No phy | sical damag | e | No | Pa | iss |
| | Tem | perature Life | 5 | Final | | No phy | sical damag | 9. | Abnormalities No | Pa | nss |
| | 10111 | LLCR | 5 | Final | 26.42 | 23.49 | 24.71 | mΩ | Abnormalities 50Max | Pa | |
| = | Miyeo | I Flowing Gas | 5 | Final | 20.42 | | sical damag | | No | Pa | |
| A-4 | IVIIXEC | LLCR | - | | 24.40 | | | | Abnormalities 50Max | | |
| - | Th | | 5 | Final | 31.49 | 25.88 | 29.40 | mΩ | No | Pa | |
| - | Inerm | al Disturbance | 5 | Final | | 1 | sical damag | | Abnormalities | Pa | |
| - | | LLCR | 5 | Final | 28.29 | 24.15 | 25.52 | mΩ | 50Max No | Pa | |
| | F | Reseating | 5 | Final | | | sical damag | - | Abnormalities | Pa | |
| | | LLCR | 5 | Final | 27.03 | 23.70 | 25.11 | mΩ | 50Max No | Pa | ISS |
| | Examination of Product 5 Final No physical damage | | | | | Abnormalities | Pa | ISS | | | |
| | Examin | ation of Product | 5 | Initial | | No phy | sical damag | е | No Abnormalities | Pa | iss |
| | | LLCR | 5 | Initial | 27.52 | 23.14 | 25.16 | mΩ | 40Max | Pa | iss |
| | Dielectric W | ithstanding Voltage | 5 | Initial | No br | eakdown | or flashover | occurred | No Abnormalities | Pa | iss |
| | F | Reseating | 5 | Final | | No phy | sical damag | е | No Abnormalities | Pa | iss |
| | Inse | ertion Force | 5 | Final | 12.67 | 9.07 | 10.51 | N | 5~20 | Pa | iss |
| | Extra | action Force | 5 | Final | 19.01 | 12.43 | 17.13 | N | 8~20 | Pa | iss |
| A-7 | [| Durability | 5 | Final | | No phy | sical damag | е | No Abnormalities | Pa | iss |
| _ | Inse | ertion Force | 5 | Final | 11.81 | 7.63 | 9.86 | N | 5~20 | Pa | iss |
| | Extra | action Force | 5 | Final | 19.2 | 11.49 | 15.66 | N | 6~20 | Pa | iss |
| | | LLCR | 5 | Final | 31.08 | 26.69 | 29.31 | mΩ | 50Max | Pa | iss |
| | Dielectric W | ithstanding Voltage | 5 | Final | No br | eakdown | or flashover | occurred | No Abnormalities | Pa | iss |
| | Insulat | ion Resistance | 5 | Final | 1.13 | 0.91 | 1.02 | 10Χ11Ω | 0.91 | Pa | iss |
| | Examin | ation of Product | 5 | Final | | No phy | sical damag | е | No Abnormalities | Pa | iss |
| | Examin | ation of Product | 5 | Initial | | No phy | sical damag | е | No Abnormalities | Pa | iss |
| B-1 | 4-Axis | Continuity Test | 5 | Final | Disconti | | than 1 µs all | contacts in | No | Pa | iss |
| - | | ation of Product | 5 | Final | | | series sical damag | 9. | Abnormalities No | Pa | nss |
| | | ation of Product | 5 | Initial | | | sical damag | | Abnormalities No | Pa | |
| B-6 | | | 5 | Final | 28.47 | 23.98 | 27.56 | °C | Abnormalities 30Max | Pa | |
| D-0 | | rent Rating ation of Product | 1 | | 20.47 | | sical damag | | No | | |
| | | | 5 | Final | | . , | | | Abnormalities No | Pa | |
| _ | | ation of Product | 5 | Initial | Soldera | | sical damag | | Abnormalities No | Pa | |
| C-1 | Sc | olderability | 5 | Final | Oolucia | | r coverage. | Idili 01 3370 | Abnormalities | Pa | iss |
| | Examin | ation of Product | 5 | Final | | No phy | sical damag | е | No Abnormalities | Pa | iss |
| | Examin | ation of Product | 5 | Initial | | No phy | sical damag | е | No Abnormalities | Pa | iss |
| C-2 | Wate | er Ingression | 15 | Final | N | No water I | eakage occu | rred | No Abnormalities | Pa | iss |
| | Examin | ation of Product | 5 | Final | | No phy | sical damag | е | No Abnormalities | Pa | iss |
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| | | TF Co | nnectiv | itv | PAG | zel N | 10 | | | REV | LC |